

Search Notes

Application/Control No.

10/811,854

Examiner

HUYEN D. LE

Applicant(s)/Patent under
Reexamination

HAN ET AL.

Art Unit

2615

SEARCHED

Class	Subclass	Date	Examiner
381	304, 305, 335-338, 345, 349,	4/13/2007	HL
	350		HL
	351		HL
	164		HL
	165		HL
	386		HL
381	397		HL
181	145		HL
	148		HL
	153		HL
	198		HL
181	199		HL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner